



NSAI
Standards

Irish Standard
I.S. EN ISO 20339:2017

Non-destructive testing - Equipment for eddy current examination - Array probe characteristics and verification (ISO 20339:2017)

I.S. EN ISO 20339:2017

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National Foreword

I.S. EN ISO 20339:2017 is the adopted Irish version of the European Document EN ISO 20339:2017, Non-destructive testing - Equipment for eddy current examination - Array probe characteristics and verification (ISO 20339:2017)

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EUROPEAN STANDARD

EN ISO 20339

NORME EUROPÉENNE

EUROPÄISCHE NORM

April 2017

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English Version

**Non-destructive testing - Equipment for eddy current
examination - Array probe characteristics and verification
(ISO 20339:2017)**

Essais non destructifs - Appareillage pour examen par courants de Foucault - Caractéristiques des capteurs multiéléments et vérifications (ISO 20339:2017)

Zerstörungsfreie Prüfung - Technische Ausrüstung für die Wirbelstromprüfung - Kenngrößen von Sensorarrays und deren Verifizierung (ISO 20339:2017)

This European Standard was approved by CEN on 5 February 2017.

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European foreword

This document (EN ISO 20339:2017) has been prepared by Technical Committee ISO/TC 135 "Non-destructive testing" in collaboration with Technical Committee CEN/TC 138 "Non-destructive testing" the secretariat of which is held by AFNOR.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by October 2017, and conflicting national standards shall be withdrawn at the latest by October 2017.

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Endorsement notice

The text of ISO 20339:2017 has been approved by CEN as EN ISO 20339:2017 without any modification.

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INTERNATIONAL STANDARD

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Non-destructive testing — Equipment for eddy current examination — Array probe characteristics and verification

*Essais non destructifs — Appareillage pour examen par courants
de Foucault — Caractéristiques des capteurs multiéléments et
vérifications*



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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 4, *Eddy current testing*.

Non-destructive testing — Equipment for eddy current examination — Array probe characteristics and verification

1 Scope

This document identifies the functional characteristics of eddy current array probes and their interconnecting elements and provides methods for their measurement and verification.

The evaluation of these characteristics permits a well-defined description and comparability of eddy current array probes.

Where relevant, this document gives recommendations for acceptance criteria for the characteristics.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 12718, *Non-destructive testing — Eddy current testing — Vocabulary*

ISO 15548-1, *Non-destructive testing — Equipment for eddy current examination — Part 1: Instrument characteristics and verification*

ISO 15548-2:2013, *Non-destructive testing — Equipment for eddy current examination — Part 2: Probe characteristics and verification*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 12718 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <http://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

3.1

element

single physical component such as a coil, a GMR or a Hall probe which has a basic function of excitation or reception

3.2

pattern

single physical and electronic arrangement of simultaneously active elements

3.3

sequencing

chronology of the activation of patterns

3.4

threshold

lowest acceptable sensitivity value defined in an application document

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